## CBCS SCHEME

USN

15EC63

# Sixth Semester B.E. Degree Examination, June/July 2019 **VLSI Design**

Time: 3 hrs.

Max. Marks: 80

Note: Answer any FIVE full questions, choosing ONE full question from each module.

#### Module-1

- 1 a. Derive the CMOS inverter DC characteristics graphically from p device and n device characteristics and show all operating regions. (08 Marks)
  - b. Explain the working of nMOS enhancement mode transistor with suitable diagrams.

(08 Marks)

OR

- 2 a. Derive expression for drain current in linear and saturation region for nMOS transistor.
  (08 Marks)
  - b. With neat sketches explain the CMOs P-well process steps to fabricate a CMOS inverter.
    (08 Marks)

#### Module-2

3 a. Write the lambda based design rules for separation of layers and transistors.

(06 Marks)

b. Draw circuit, stick and layout diagram for nMOS shift register cell.

(10 Marks)

OR

- Define sheet resistance (R<sub>S</sub>) standard unit of capacitance (□Cg) and delay unit (τ) (06 Marks)
  - b. Calculate the capacitance of the structure given below in Fig.Q4(b).

(10 Marks)

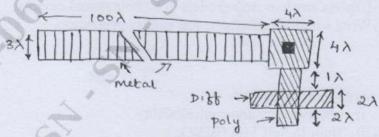


Fig.Q4(b)

Area capacitance value for metal 1 to substrate  $= 0.3 \text{pF} \times 10^{-4}/\mu\text{m}^2(0.075 \text{ relative value})$ Area capacitance value for diffusion to substrate  $= 1 \text{pf} \times 10^{-4}/\mu\text{m}^2(0.25 \text{ relative value})$ Area capacitance value for polysilicon to substrate  $= 0.4 \text{ pF} \times 10^{-4}/\mu\text{m}^2(0.1 \text{ relative value})$ .

### Module-3 owing device

- 5 a. Obtain the scaling factor for the following device parameters:
  - i) gate capacitance
  - ii) gate area
  - iii) saturation current (Idss)
  - iv) channel resistance (Ron)
  - v) maximum operating frequency (f<sub>0</sub>)
  - vi) power dissipation per gate (Pg)
  - vii) current density (J)
  - viii) gate delay (T<sub>d</sub>).

(08 Marks)

b. With a neat diagram explain  $4 \times 4$  Barrel shifter.

(08 Marks)

OR

6 a. Explain the general arrangement of a 4 bit data path for processor.

(08 marks)

b. Describe Manchester carry chain element.

(08 Marks)

#### Module-4

- 7 a. Discuss the architectural issues to be followed in the design of VLSI sub system. (05 Marks)
  - b. Explain in detail the general structure of an FPGA fabric.

(06 Marks)

- c. Explain switch logic implementation of CMOS 5 way selector with neat circuit diagram.
  - (05 Marks)

OR

8 a. Explain the structured design approach for the implementation of a parity generator.

(08 marks)

b. Explain dynamic CMOS logic with example.

(08 Marks)

#### Module-5

9 a. Explain 3 transistor dynamic RAM cell with schematic diagram.

(06 Marks)

b. Explain any two fault models in combinational circuits.

(06 Marks)

e. Write a note on automatic test pattern generation.

(04 Marks)

OR

- 10 a. write short notes on:
  - i) observability and controllability

ii) Built In Self Test (BIST).

(08 Marks)

b. Explain nMOS pseudo static RAM cell with schematic diagram.

(08 Marks)

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